

HAWKEYE[®] by LiteSentry[™] **Glass Inspection System for Scratches and Defects**

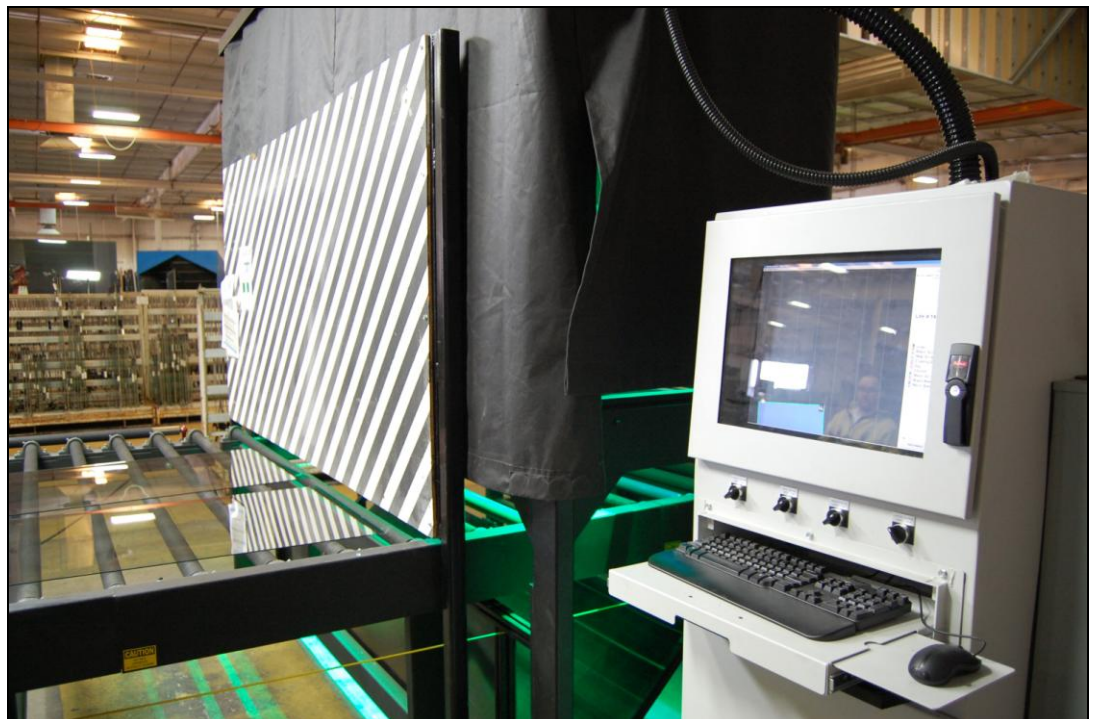


- ◆ Hawkeye[®] by LiteSentry[™]
- ◆ High-resolution camera-based inspection system for glass.
- ◆ Inspects both front and rear surfaces of monolithic glass moving on the fabrication line.
- ◆ On-line defect inspection system operates at conveyor velocities up to 700 mm/s.
- ◆ Integrates seamlessly into IG, tempering, laminating or coating lines.
- ◆ Prevents defects from proceeding to high value-added operations.
- ◆ Keeps defects out of your customer's sight.
- ◆ Improved quality = increased profit.

Applications:

- ◆ **Flat glass fabrication including Tempering, Coating, and final packaging.**
- ◆ **Modular system applies to any line width.**

LiteSentry



System in operation at flat glass tempering line

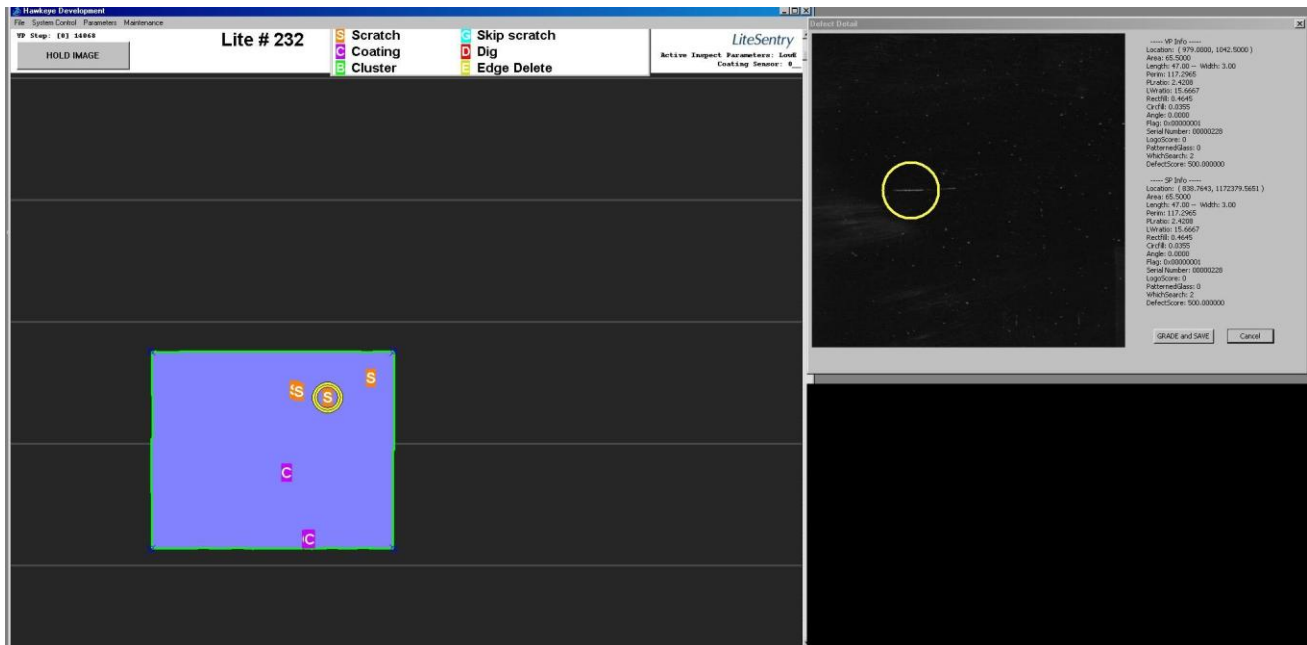
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Setting the Standard in Glass Inspection

Patented / Patent Pending

SPECIFICATIONS

Hawkeye® by LiteSentry™ Scratch and Defect Inspection System



Accuracy:

- 200 /20 per MIL-C-48497A.
- This standard MIL specification is broadly used in the optical coating industry. 200 / 20 defines scratches and digs (defects of non-linear geometry). 200 = 0.20 mm scratch width by length defined by user. 20 = 0.2 mm diameter dig.

Types of defects detected:

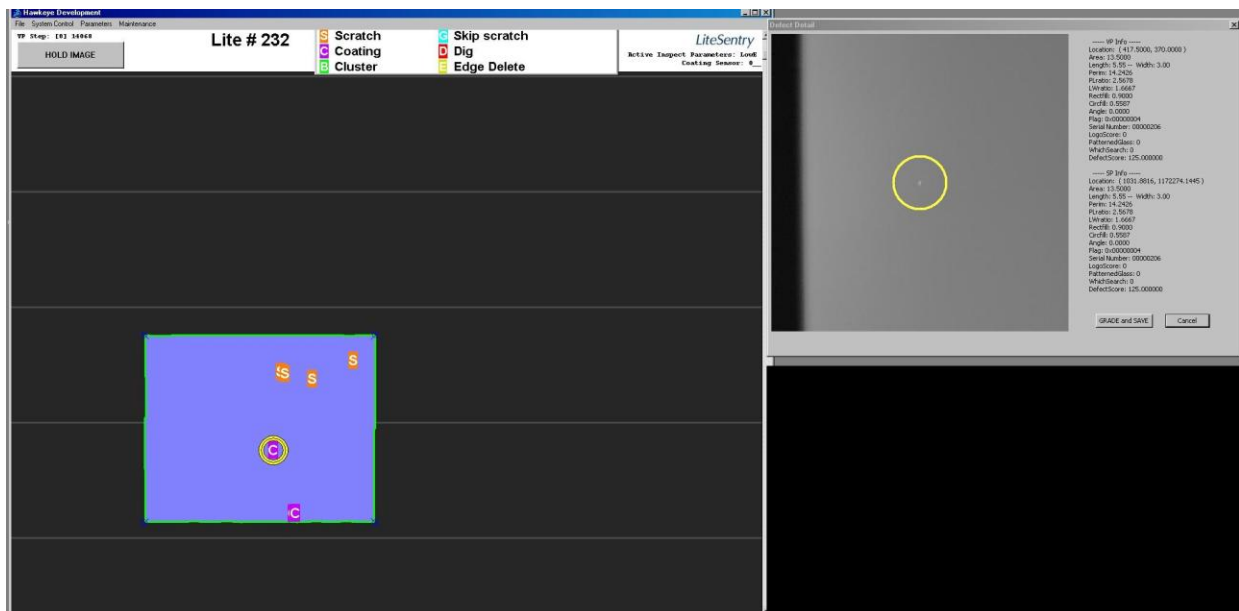
- Scratch, dig, surface pit or debris, coating pinhole, coating spot cluster, tin spot, abrasion, fingerprint, skid mark, tire mark, seed, stone, laminate inclusion, edge delete skip, low E edge grind faults, and many others.

Tempering logo logic:

- Tempering logos are identified and checked for proximity to appropriate corner location. Out of place or missing tempering logos are noted to operator.

Database:

- Extensive information for each defect is logged to an SQL database. User may run reports to sort defects by type, location, glass size, date, time, or additional parameters.



Display with pop-up of coating defect